

Docket No. 4007734 FPS/MMCS/APC

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PATENT/OFFICIAL

AUG 11 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Joseph Young J. PAIK

Serial No. 10/665,165

Filed: September 18, 2003

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: Group Art Unit:  
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: Examiner:

For: FEEDBACK CONTROL OF A CHEMICAL MECHANICAL POLISHING PROCESS  
FOR MULTI-LAYERED FILMS

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Honorable Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom. Copies of any cited U.S. Patents and U.S. Patent Publications are not being submitted in accordance with 37 CFR 1.98(a)(2)(i).

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

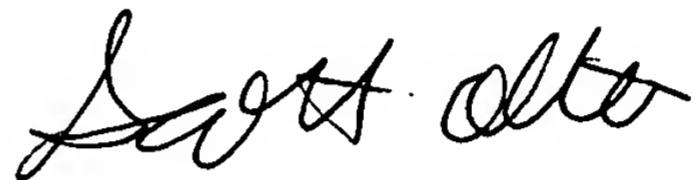
In accordance with 37 C.F.R. § 1.97(g) and (h), the filing of this IDS should not be construed as a representation that a search had been made or that information cited is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56 (b), or that any cited document listed or attached is (or constitutes) prior art. Unless otherwise indicated, the date of

publication indicated for an item is taken from the face of the item, and Applicant reserves the right to prove that the date of publication is in fact different.

No fee is believed to be required; however, the Commissioner is authorized to charge any deficiency in any fees pursuant to 37 CFR § 1.17 associated with this communication and to credit any excess payment to Deposit Account No. 08-0219.

Respectfully submitted,

WILMER CUTLER PICKERING HALE AND DORR LLP



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Registration No. 32,879

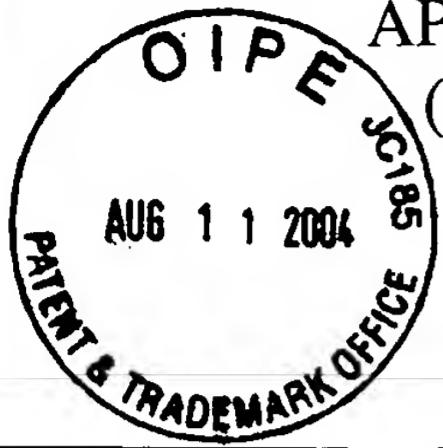
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Date: 8/11/04

| <b>INFORMATION DISCLOSURE<br/>CITATION IN AN<br/>APPLICATION<br/>(PTO-1449)</b>   |                 |          |                         | ATTY. DOCKET NO.<br>007734 FPS/MMCS/APC | SERIAL NO.<br>10/665,165 |             |
|---|-----------------|----------|-------------------------|---|--------------------------|-------------|
|  |                 |          |                         | APPLICANT<br>Joseph Young J. PAIK       |                          |             |
|   |                 |          |                         | FILING DATE<br>September 18, 2003       |                          | GROUP       |
| <b>U.S. PATENT DOCUMENTS</b>  |                 |          |                         |   |                          |             |
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| EXAMINER  |                 |          |                         | DATE CONSIDERED                         |                          |             |

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION  
(PTO-1449)

ATTY. DOCKET NO.  
007734 FPS/MMCS/APCSERIAL NO.  
10/665,165APPLICANT  
Joseph Young J. PAIKFILING DATE  
September 18, 2003

GROUP

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|  |            |   |                                     |                          |          |                                     |                          |    |                                     |                          |
|--|------------|---|-------------------------------------|--------------------------|----------|-------------------------------------|--------------------------|----|-------------------------------------|--------------------------|
| <b>INFORMATION DISCLOSURE<br/>CITATION IN AN<br/>APPLICATION<br/>(PTO-1449)</b>  |            | ATTY. DOCKET NO.<br>007734 FPS/MMCS/APC |                                     | SERIAL NO.<br>10/665,165 |          |                                     |                          |    |                                     |                          |
|  |            | APPLICANT<br>Joseph Young J. PAIK       |                                     |                          |          |                                     |                          |    |                                     |                          |
|  |            | FILING DATE<br>September 18, 2003       |                                     | GROUP                    |          |                                     |                          |    |                                     |                          |
| <b>FOREIGN PATENT DOCUMENTS</b>  |            |   |                                     |                          |          |                                     |                          |    |                                     |                          |
| EXAMINER'S<br>INITIALS   | PATENT NO. | DATE                                    | COUNTRY                             | CLASS                    | SUBCLASS | Translation                         |                          |    |                                     |                          |
|  |            |   |                                     |                          |          | <input checked="" type="checkbox"/> | <input type="checkbox"/> |    |                                     |                          |
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| GB 2 365 215 A   | 02/13/02   | GB                                      | <input checked="" type="checkbox"/> | <input type="checkbox"/> |          |                                     |                          |    |                                     |                          |
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| <b>FILING DATE</b><br>September 18, 2003   |  | <b>GROUP</b>                            |                          |
| <b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>              |  |   |                          |
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